

Substrate Coupling: Modeling and Mitigation Techniques

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ECE 465: Performance Issues in VLSI IC Design

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Outline

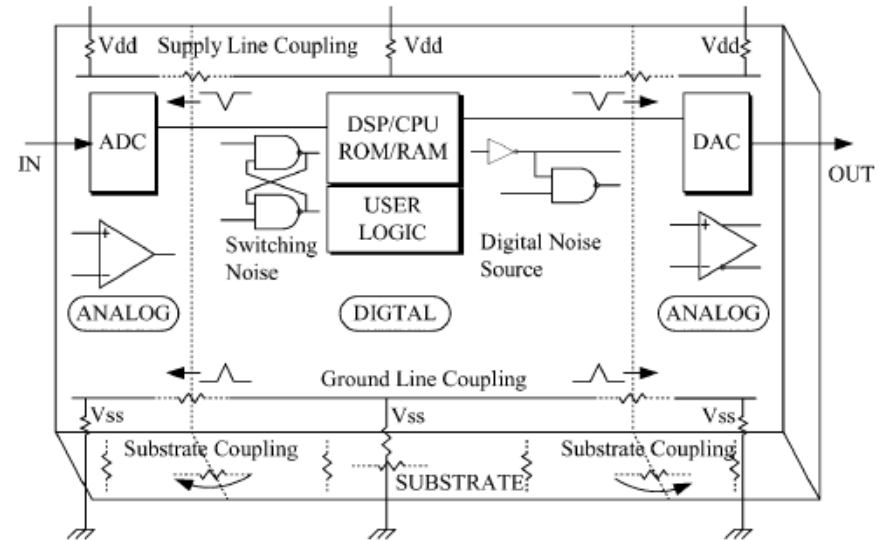
- Substrate coupling mechanism
- Modeling techniques
- Mitigation techniques
- Conclusions
- Future directions

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- **Substrate coupling mechanism**
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What is Substrate Coupling?

- Substrate coupling
 - Coupling of digital switching noise to analog/RF circuits through substrate
- Why it is undesired?
 - Causes voltage fluctuations
 - Signal leakage causes power loss
 - Degrades performance of sensitive amplifiers, oscillators[#]



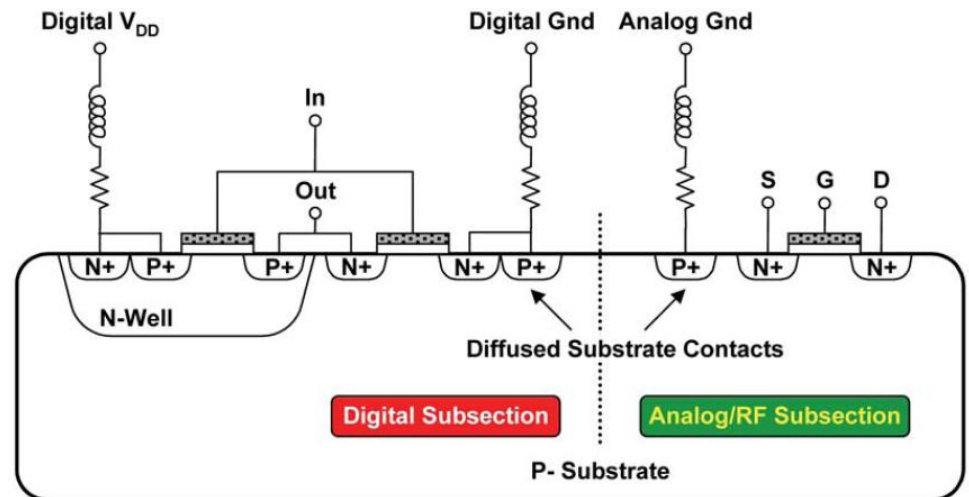
Substrate coupling noise in mixed-signal SoC

Afzali-Kusha *et al.*, “[Substrate Noise Coupling in SoC Design: Modeling, Avoidance, and Validation](#),” in *Proceedings of the IEEE*, 2006.

B. R. Stanistic *et al.*, “[Addressing substrate coupling in mixed-mode ICs: Simulation and power distribution systems](#),” *IEEE J. Solid-State Circuits*, vol. 29, no. 3, pp. 226–238, Mar.1994.

Impact of Substrate Coupling on Circuit Performance

- Operating conditions
 - Threshold voltage modulation
 - Bias current
- Degradations
 - Gain, bandwidth
 - Jitter, SNR
- Failures
 - Latchup



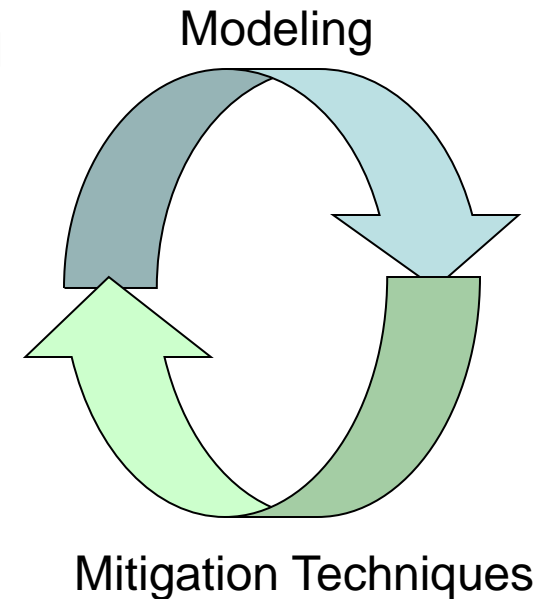
*Noise coupling from switching portion of an IC

Ranjit Gharpurey and Edoardo Charbon, "[Substrate Coupling: Modeling, Simulation and Design Perspectives](#)," in *Proceedings of the International Symposium on Quality Electronic Design*, pp. 283-290, 2004.

* Afzali-Kusha et al., "[Substrate Noise Coupling in SoC Design: Modeling, Avoidance, and Validation](#)," in *Proceedings of the IEEE*, 2006.

Substrate Coupling Methodologies

- Two aspects of substrate coupling research
 - Modeling the substrate coupling
 - Substrate extraction
 - Parasitics extraction
 - Techniques to mitigate the coupling noise
 - Physical design techniques
 - Circuit based technique
- Accurate modeling enables better mitigation techniques

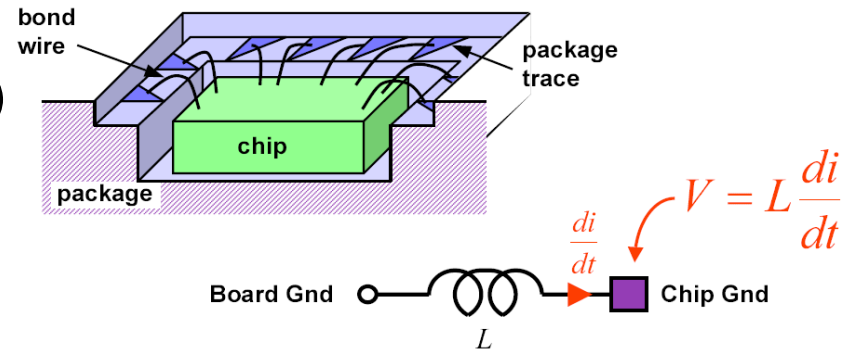
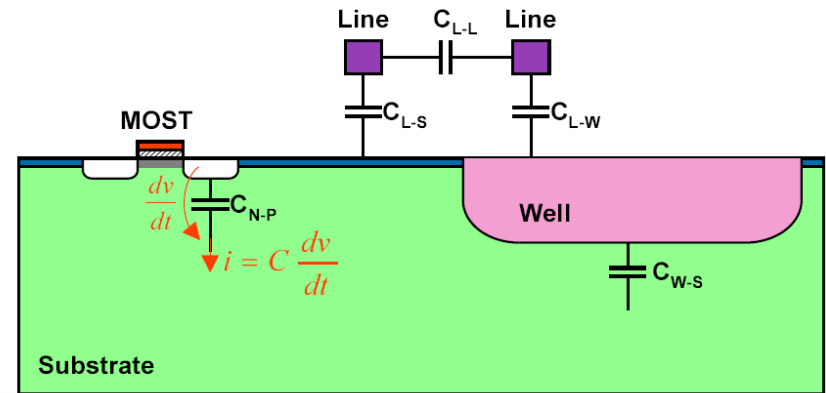


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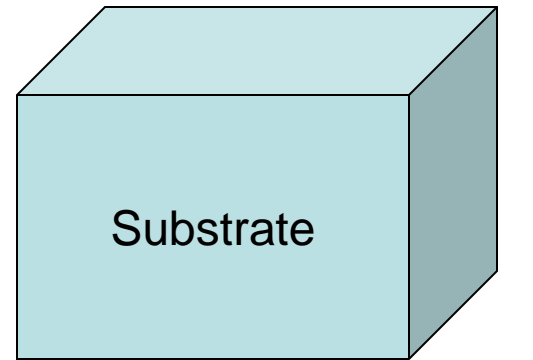
Substrate Coupling at Various Level

- Impact ionization
 - **At device level**
 - Substrate current injection
- Capacitive coupling ($C \cdot dv/dt$)
 - **At circuit level**
 - Due to junction capacitance
 - Interconnect capacitance to substrate
- Inductive ($L \cdot di/dt$) and resistive ($i \cdot R$) noise
 - **At chip level**
 - Large di/dt on power supply at high frequency
 - Resistive drop at low frequency

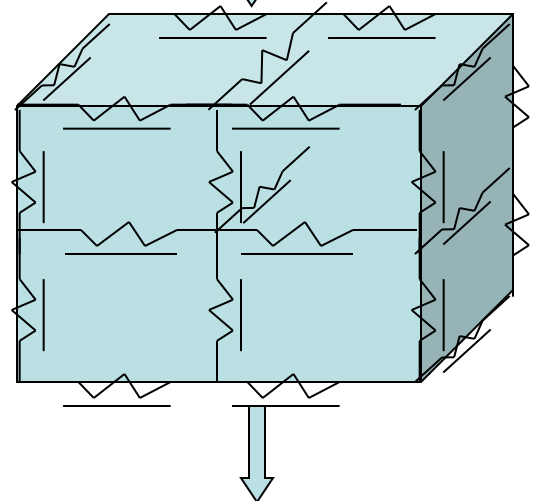


Substrate Extraction

- Extraction
 - Process by which an RC equivalent circuit of the substrate is determined
- Accomplished by solving electromagnetic differential equations
- Extracted RC mesh is simulated using SPICE
- RC values are incorporated
 - Post layout SPICE simulation



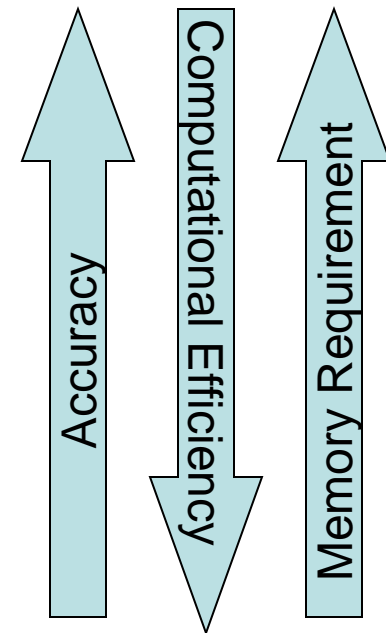
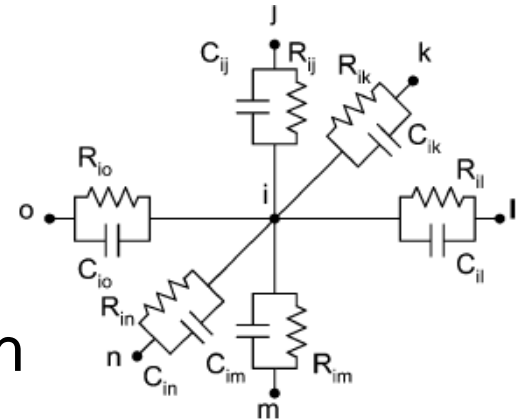
Substrate Extraction



Post layout SPICE simulation

Modeling Coupling to Substrate

- Integral-equation technique
 - Distributed RC mesh
- Solution techniques to model RC mesh
 - Finite elements (FEM)
 - Exact solution using Poisson and continuity equations
 - Finite differences (FDM)
 - Simple RC model applied on 3D Mesh
 - Boundary element (BEM)
 - Only port-to-port relationship needs to be modeled



Small Circuit Extraction

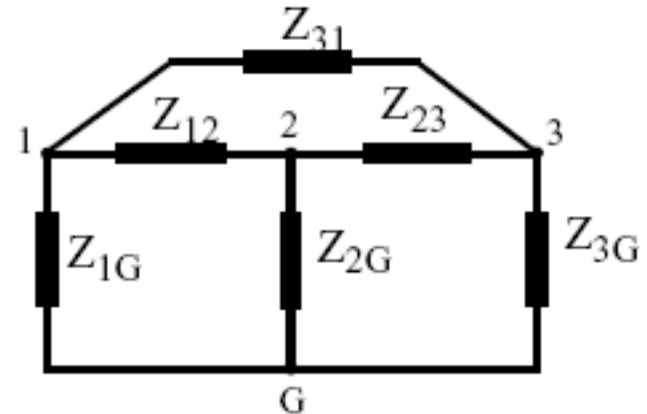
- Lumped models

- Advantages

- Accuracy ↑

- Drawbacks

- Extraction/ Simulation time ↑

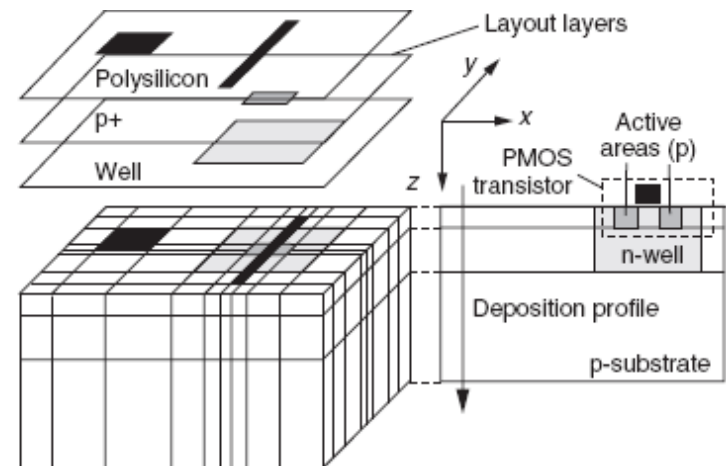


- Distributed models

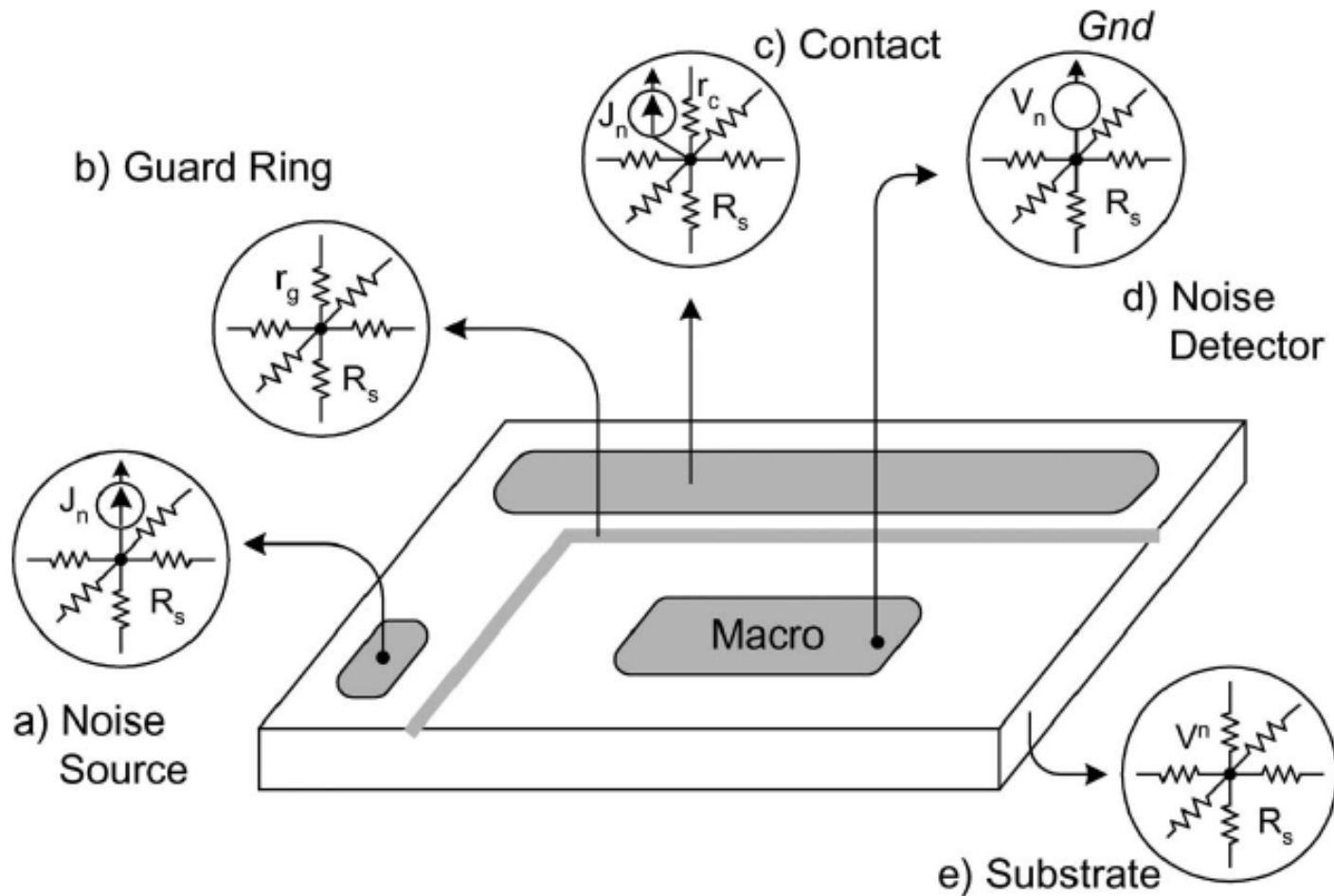
- Appropriate formulation of substrate electromagnetic interactions

- Rely on numerical methods

- MEDICI, PISCES

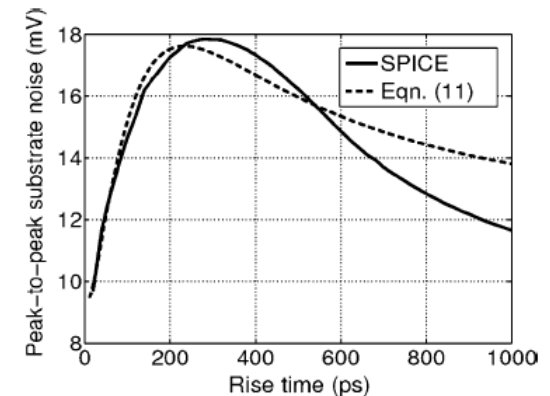
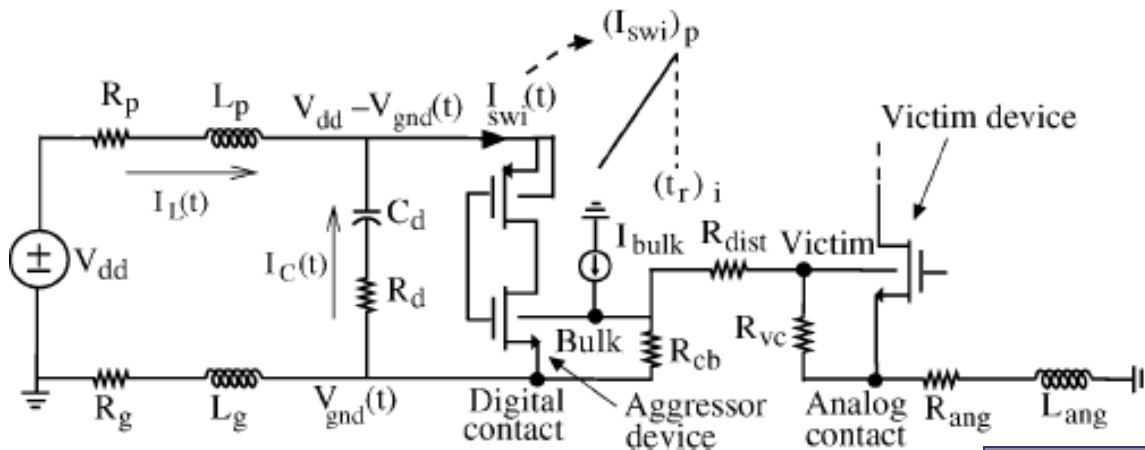


Substrate Resistive Macro-model



Analysis using Macro-models

- Macro-model presented here helps in early stage of design process
 - Evaluates the dominant substrate coupling mechanism
 - Exhibits a maximum error of ~18.4%; Mainly due to
 - Approximation of noise as a ramp function
 - Feedback effect of the nonlinear devices are ignored in the model

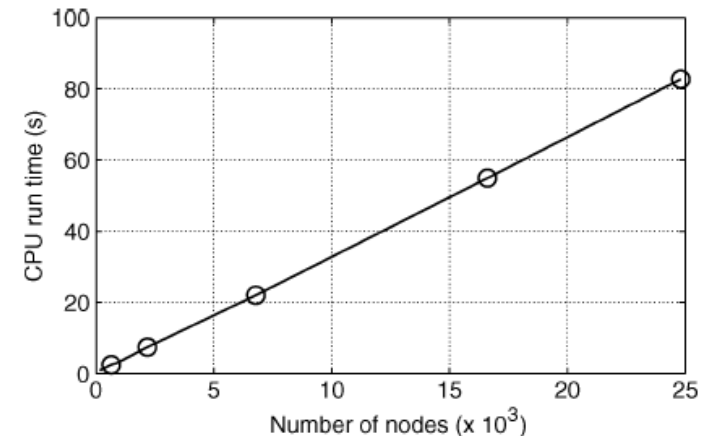
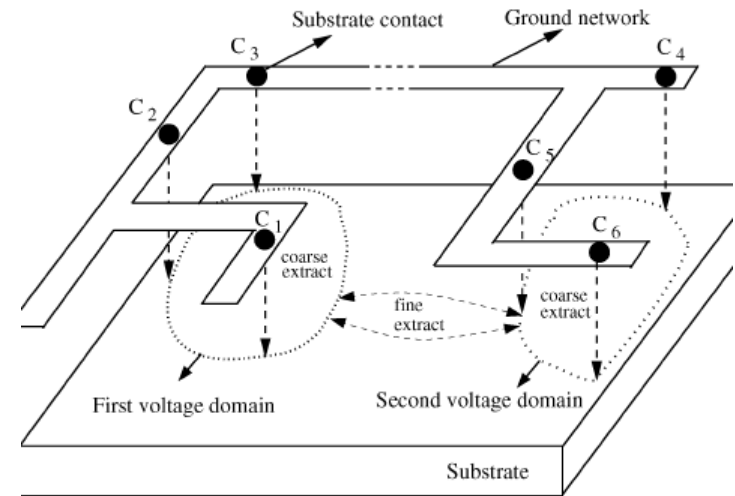


$$(V_{s-total})_{pp} \approx (V_{s-gnd})_{pp} + (V_{s-bulk})_p.$$

$$(V_{s-bulk})_p \approx (I_{bulk})_p \frac{R_{cb}}{R_{cb} + R_{dist} + R_{vc}} \times \left(R_{ang} + R_{vc} + \frac{L_{ang}}{t_r} \right).$$

Large Scale Mixed-Signal Circuits

- Transistor level simulation is not feasible for large-scale circuits
 - Nonlinear nature of the device models
 - Computationally inefficient
- Voltage domains on the substrate
 - Coarse extraction in each domain to reduce the computational complexity
 - Followed by a fine extraction of those domains where the dominant current flow occurs
 - Linear complexity of algorithm



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Physical Design Techniques

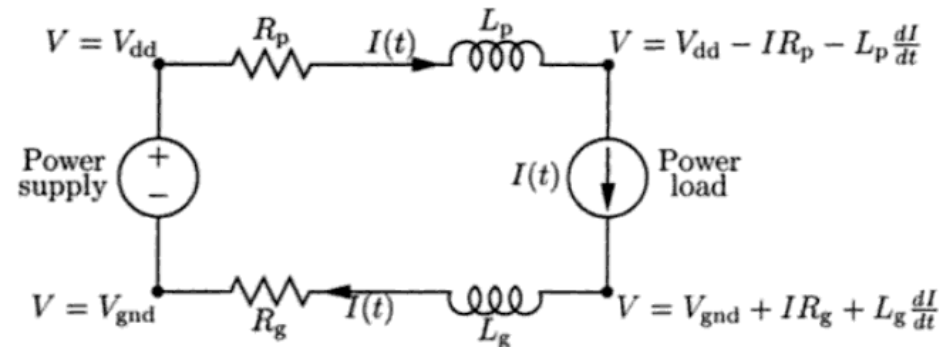
- Power network design techniques
 - At high frequency inductance noise dominates
 - Special care to minimize di/dt

$$V_{\text{drop}} = Ri + L \frac{di}{dt}$$

- Architectural solutions to di/dt
 - RAZOR flip flops*
 - Traditional sensor based control#

- Mainly to solve low or mid range inductive noise

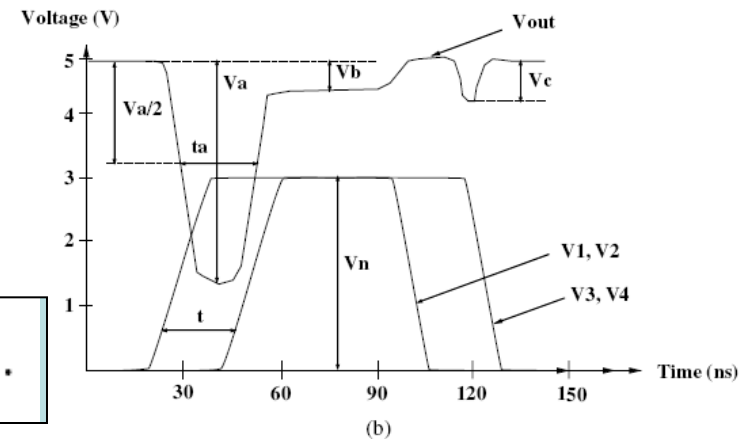
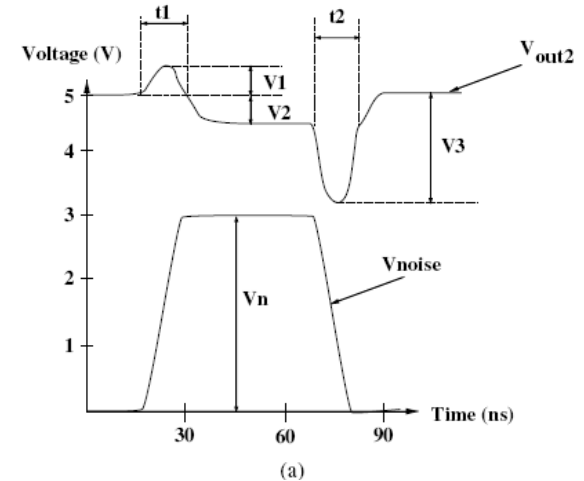
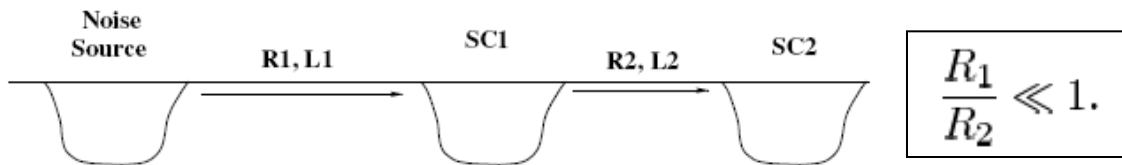
- High frequency inductive noise
 - No architectural solution exist
 - Only circuit based solutions
 - Use of decoupling capacitors



Physical Design Techniques - 2

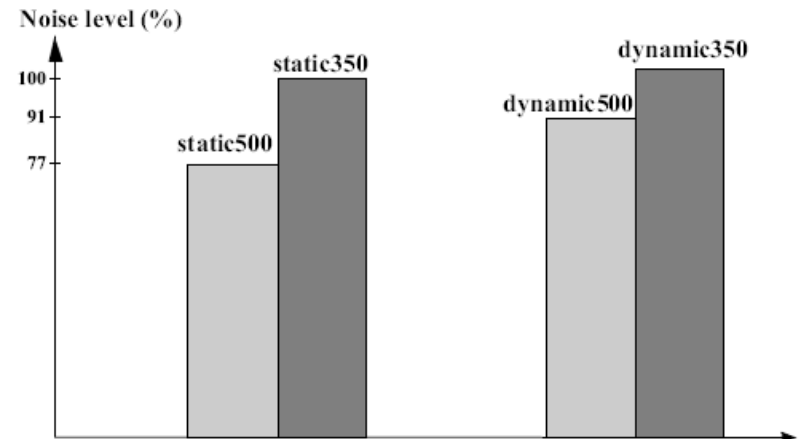
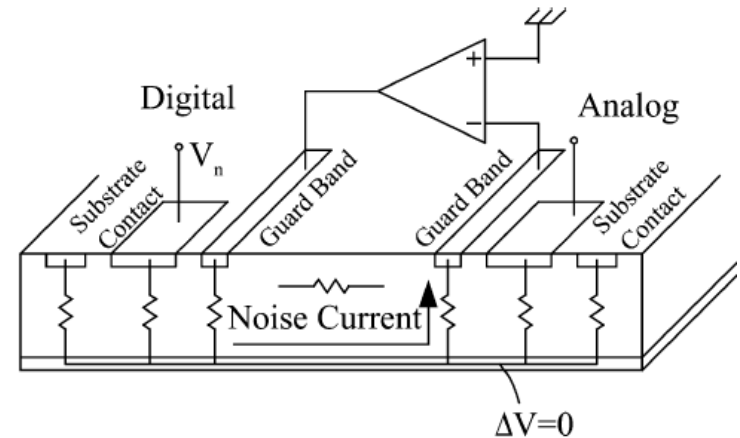
- Layout techniques to improve the uniformity
 - A compact layout is beneficial to improve the uniformity of the substrate noise received by the different transistors

- Placement of substrate contact



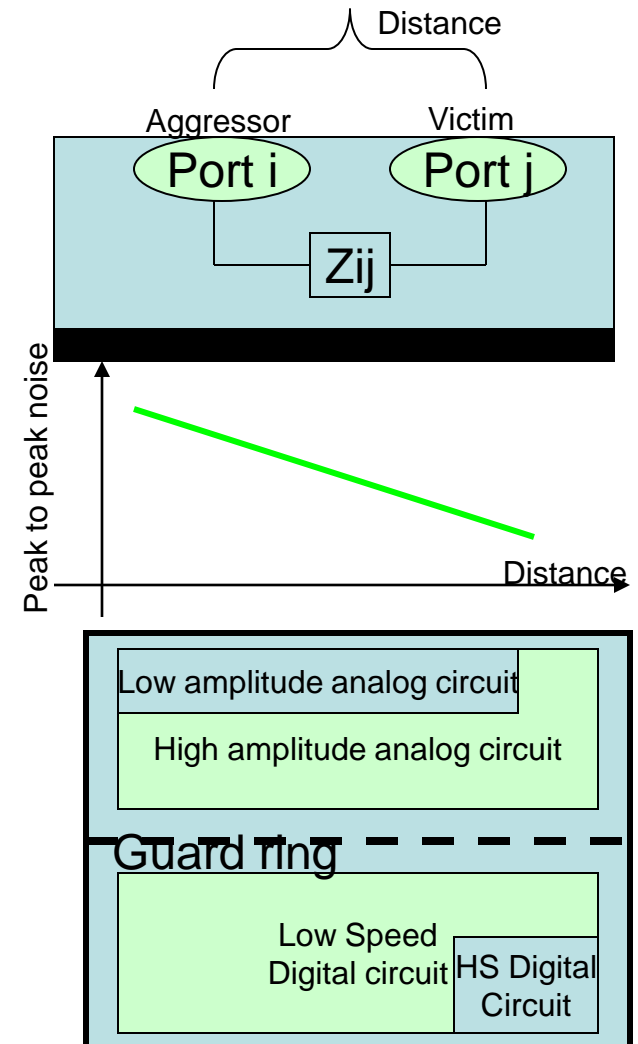
Circuit Design Techniques

- Active guard band filters
- Active cancellation circuits
 - Differential ended analog circuits
 - Repeater insertion for improved noise immunity
- Register positioning and orientation to minimize noise
 - Static register as oppose to dynamic registers
- Choice of logic family also plays an important role in noise mitigation



Isolation Techniques

- Separate digital and analog supply
 - Switching noise is not coupled from one domain to other domain
- Distance isolation
 - Reduces the amplitude of noise
- Isolation of noise source
 - Ensures that noise is not injected
- Careful floorplanning
 - Place sensitive digital and analog blocks ***furthest*** from each other



Guidelines to Mitigate Noise

- Separate analog and digital power lines
- Physically separate the noise generating circuit and noise sensitive circuit
- Guard ring with good substrate contacts placed between digital and analog circuits
 - Connect the rings to external “quiet” ground
- Differential ended analog circuits
 - Robust and have good noise rejection capability
 - Good CMRR and PSRR

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Conclusions

- Switching noise of digital block affects sensitive analog/RF blocks through substrate coupling
- Modeling the substrate coupling with high accuracy for large chips is a daunting and resource consuming task
- Multiple techniques – physical and circuit based – should be used to mitigate substrate coupling noise
- Scaling of feature size and supply voltage would exacerbate the problem of the substrate coupling noise

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Future Directions

- Hard problems and open challenges
 - Related with modeling of large circuits
 - Computational complexity
 - Memory requirement
 - CAD tools and EDA flow
 - Integration of accurate substrate models into existing CAD flow

“All models are wrong, some are useful”
-- George E. P. Box

So another never-ending task for any research field is to

“Keep devising new models and macro-models”

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